

Notice of References Cited

Application/Control No.

10/571,464

Applicant(s)/Patent Under
Reexamination
STEFFL, UDO

Examiner

RIP A. LEE

Art Unit

1796

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,114,522	05-1992	Takado et al.	156/245
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number	Date	Country	Name	Classification
		Country Code-Number-Kind Code	MM-YYYY			
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
U					
V					
W					
X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.